SEMICAPS 4000

INVERTED ANALYTICAL AND TESTER-DOCKED SYSTEM

photo are for illustration only

Tester-Docked Conversion

Features

- Analytical or ATE docked configuration
- 300 mm wafer stage including auto-lock compatible with Probe Cards and manipulators
- Docks easily to Tester or Probe Station
- High resolution stage with 0.5 µm repeatability
- Aplanatic Refractive Solid Immersion Lens (ARSIL) option, currently probing 3nm nodes
- CAD interface option
- Techniques include a combination of:
  - Laser Timing Probe (LTP)
    Scanning Optical Microscopy (SOM) with best sensitivity
    static: TIVA, OBIRCH
    dynamic: LADA, SDL
  - Photon Emission Microscopy (PEM) with various options for the InGaAs or Si-CCD camera
  - Thermal Microscopy (THM) with InSb camera

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